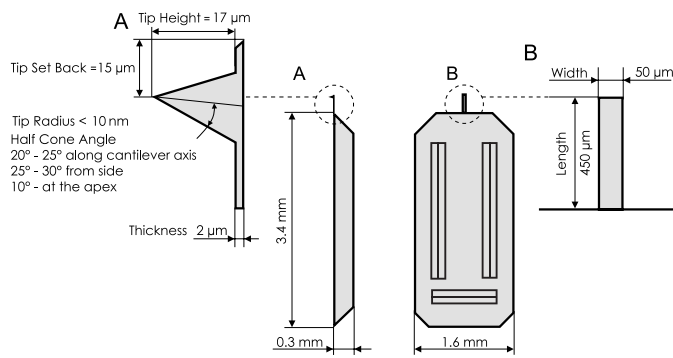




AFM probe Model: **Contact-G**



- Contact Mode
- Rotated Monolithic Silicon Probe
- Symmetric Tip Shape
- Chipsize: 3.4 x 1.6 x 0.3 mm
- Coating: none
- This probe uses an “on scan angle” symmetric tip to provide a more symmetric representation of features over 200 nm.



	Typical Values	Range
Resonant Frequency	13 kHz	+/- 4 kHz
Force Constant	0.2 N/m	0.07 - 0.4 N/m
Cantilever Length	450 μm	+/- 10 μm
Mean Width	50 μm	+/- 5 μm
Thickness	2 μm	+/- 1 μm
Tip Height	17 μm	+/- 2 μm
Tip Set Back	15 μm	+/- 5 μm
Tip Radius	< 10 nm	
Coating	none	
Half Cone Angle	20° - 25° along cantilever axis 25° - 30° from side 10° at the apex	

Order Code	Units in Package	Coating	Price
Contact-G-10	10 pieces	none	\$200
Contact-G-50	50 pieces	none	\$850
Contact-G-W	380 pieces	none	\$3800